

ABSTRACT

An electronic device testing apparatus for
5 conducting a test by pressing input/output terminals of
an IC to be tested against sockets (50), comprising a
pusher (30) provided at least with a pusher base (34)
provided to be able to approach and separate with respect
to said sockets (50), a lead pusher base (35) fixed to
10 said pusher base (34), a pusher block (31) for pressing
against said sockets (50) by contacting said IC to be
tested from an opposite face of said socket (50), a load
base (32) attached with the pusher block (31), and two
springs (36, 38) for giving an elastic force in the
15 direction of pressing the IC to be tested to the pusher
block (31) via the load base (32), wherein the load base
(32) and the springs (36, 38) are sandwiched with the
lead pusher base (35) and the pusher base (34), and the
pusher block (31) is detachably attached to the load base
20 (32) via an opening portion provided to the pusher base
(34).